


Search Notes 	Application/Control No. 10571862	Applicant(s)/Patent Under Reexamination IP, CHARLOTTE
	Examiner Young J Kim	Art Unit 1637

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
searched patent databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB)	2/15/2008	YJK
see enclosed for text-search strategy	2/15/2008	YJK
STIC assisted search of SEQ ID Numbers 1-4; (commercial, patent, and published databases)	2/15/2008	YJK

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner